

A set of large time-step integration formulas

Kukk, Vello ECS'03 : proceedings of the 4th Electronic Circuits and Systems Conference : September 11-12, 2003, Bratislava, Slovakia 2003 / p. 151-154 : ill

Automated design and diagnosis of electronic system based on description language representation

Wawryn, Krzysztof; Drabarek, Jozef **BEC** : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 443-448 https://www.ester.ee/record=b2150914*est

Automatic circuit partitioning for FPGAs

Krupnova, Helena; Abbara, A.; Brasen, D.; Saucier, Gabriele **BEC'96** : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 389-392: ill

Boole'i algebra kasutamine automaatikalülituste projekteerimisel : loengukonspekt

Agur, Ustus 1972 https://www.ester.ee/record=b1327567*est

Calculation of probabilistic testability measures for digital circuits with Structurally Synthesized BDDs

Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan Microprocessors and microsystems 2020 / art. 103117, 12 p <https://doi.org/10.1016/j.micpro.2020.103117> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Chaos in electronic circuits

Lindberg, Erik **BEC** : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 29-37: ill

Combinational fault simulation in sequential circuits

Ubar, Raimund-Johannes; Kõusaar, Jaak; Gorev, Maksim; Devadze, Sergei 2015 IEEE International Symposium on Circuits and Systems : 24-27 May 2015, Lisboa, Portugal : [proceedings] 2015 / p. 2876-2879 : ill <https://doi.org/10.1109/ISCAS.2015.7169287> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Complex delay fault reasoning with sequential 7-valued algebra

Kõusaar, Jaak; Ubar, Raimund-Johannes; Alekseev, Igor 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2015.7102403>

Computational aspects of nodal method for simulation of electronic circuits

Laksberg, Edgar 1983

Computer-aided examination of the P^L current source and the behaviour of the P^L flip-flop used in static memory cells

Rang, Toomas Periodica polytechnica. Electrical engineering = Электротехника 1981 / p. 159-165 : joon https://www.ester.ee/record=b1198855*est <https://pp.bme.hu/ee/article/view/4776/3881>

Conditional fault collapsing in digital circuits with shared structurally synthesized BDDs [Online resource]

Jürimägi, Lembit; Ubar, Raimund-Johannes **BEC 2018** : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p. : ill <https://doi.org/10.1109/BEC.2018.8600967>

Critical path tracing based simulation of transition delay faults

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan 2014 17th Euromicro Conference on Digital System Design : DSD 2014 : 27-29 August 2014, Verona, Italy : proceedings 2014 / p. 108-113 : ill

Critical path tracing based simulation of transition delay faults

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 61-66 : ill

Defect-oriented library builder and hierarchical test generation

Cibakova, Tatiana; Gramatova, Elena; Kuzmich, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 163-168 : ill

Defects, faults and fault models

Gramatova, Elena; Fisherova, Maria; **Ubar, Raimund-Johannes**; Pleskacz, Witold A. Handbook of testing electronic systems 2005 / p. 26-96 : ill

Design error diagnosis in digital circuits with stuck-at fault model

Jutman, Artur; Ubar, Raimund-Johannes Microelectronics reliability 2000 / 2, p. 307-320 : ill

Deterministic defect-oriented test generation for combinational circuits

Raik, Jaan; Ubar, Raimund-Johannes; Sudbrock, Joachim; Kuzmich, Wieslaw; Pleskacz, Witold A. LATW 2005 : 6th IEEE Latin-American Test Workshop : March 30 - April 2, 2005, Salvador, Bahia, Brazil : [digest of papers] 2005 / p. 325-330 : ill

Diagnostics system for electronic circuits

Melentjev, Sergei 11th International Symposium "Topical Problems in the Field of Electrical and Power Engineering." Doctoral School of Energy and Geotechnology II : Pärnu, Estonia, January 16-21, 2012 2012 / p. 192-194 : ill

Digitaalsüsteemide diagnostika

Ubar, Raimund-Johannes 2005 http://www.ester.ee/record=b2097071*est

Efficient at-speed interconnect BIST and diagnosis framework

Jutman, Artur Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. 257-258 : ill https://artiklid.elnet.ee/record=b1018804*est

Ein universeller Weg zur Automatisierung des Testentwurfs für digitale Objecte

Ubar, Raimund-Johannes; Lohuaru, Tõnu Fehler in Automaten 1989 / S. 16-30 : ill

Electronic circuits : examples for project based subject "Technologies of electronic products"

Sillakivi, Peeter; Tamm, Uljas 2003 https://www.ester.ee/record=b1828290*est

Elektronilülitused : näidiskeemid projektipõhilisele õppeainele "Elektrontoodete tehnoloogiad"

2003 https://www.ester.ee/record=b1828299*est

European Test Symposium : ETS 2005 : 22-25 May 2005, Tallinn, Estonia : proceedings

Cantarella, JD 2005 https://www.ester.ee/record=b2300865*est

Evolutionary approach to test generation for functional BIST

Skobtsov, Y.A.; Ivanov, D.E.; Skobtsov, V.Y.; **Ubar, Raimund-Johannes; Raik, Jaan** Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005 2005 / p. 151-155 : ill https://artiklid.elnet.ee/record=b1018764*est

Exact parallel critical path fault tracing to speed-up fault simulation in sequential circuits

Kõusaar, Jaak; Ubar, Raimund-Johannes; Kostin, Sergei; Devadze, Sergei; Raik, Jaan International journal of microelectronics and computer science 2018 / p. 9-18 <https://ijmcs.dmcps.pl/web/guest/vol.-9-no.-1>
https://ijmcs.dmcps.pl/documents/10630/345460/IJMCS_1_2018_2.pdf

Experimental performance validation of Z-source DC circuit breaker for high impedance faults

Pogulaguntla, Aditya; Naik Banavath, Satish; **Chub, Andrii; Vinnikov, Dmitri;** Singh, Rajendra 2024 IEEE Sixth International Conference on DC Microgrids (ICDCM) 2024 / 5 p <https://doi.org/10.1109/ICDCM60322.2024.10664702>

Fast and efficient static compaction of test sequences using bipartite graph representations

Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes ECS'99 : proceedings of the 2nd Electronic Circuits and Systems Conference : September 6-8, 1999, Bratislava, Slovakia 1999 / p. 17-20

Fast identification of true critical paths in sequential circuits

Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan; Jürimägi, Lembit Microelectronics reliability 2018 / p. 252-261 : ill <https://doi.org/10.1016/j.microrel.2017.11.027> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Fault simulation with parallel exact critical path tracing in multiple core environment

Gorev, Maksim; Ubar, Raimund-Johannes; Devadze, Sergei 2015 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2015 / p. 1180-1185 : ill

Handbook of testing electronic systems

Novak, Ondrej; Gramatova, Elena; **Ubar, Raimund-Johannes; Jutman, Artur; Raik, Jaan** 2005 https://www.ester.ee/record=b2102523*est

Hierarchical identification of NBTI-critical gates in nanoscale logic

Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Hierarchical identification of untestable faults in sequential circuits

Raik, Jaan; Ubar, Raimund-Johannes; Krivenko, Anna; Kruus, Margus 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 668-671 : ill <http://dx.doi.org/10.1109/DSD.2007.4341539>

Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

Jenihhin, Maksim; Squillero, Giovanni; Tihomirov, Valentin; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <https://doi.org/10.1007/s10836-016-5589-x> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Identification and rejuvenation of NBTI-critical paths in nanoscale logic circuits

Jenihhin, Maksim 1st International Workshop on Reliability and Aging in Forthcoming Electronic Systems : May 28-29, 2015, Cluj-Napoca, Romania 2015 / [1] p

Impulss-seadmed : laboratoorne töö nr. 5 : trigerid loogikaelementidel

1986 https://www.ester.ee/record=b1240931*est

Impulss-seadmed : laboratoorne töö nr. 8 : lineaarpinge generaator

1986 https://www.ester.ee/record=b2618544*est

Informal Digest of Papers : 10 IEEE European Test Symposium : Tallinn, Estonia, May 22-25, 2005

2005 https://www.ester.ee/record=b2055139*est

Investigating defects in digital circuits by Boolean differential equations

Kruus, Helena; Orasson, Elmet; Robal, Tarmo; Ubar, Raimund-Johannes The 4th International Conference "Distance Learning - Educational Sphere of XXI Century" (DLESC'04) 2004 / p. 432-435

Low frequency acoustic method to measure the complex bulk modulus of porous materials

Napolitano, Marialuisa; Di Giulio, Elio; **Auriemma, Fabio** The Journal of the Acoustical Society of America 2022 / art. 1545
<https://doi.org/10.1121/10.0009767> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Low voltage 2-GHz GaAs transmitter circuit modules

Kalajo, Sami; Kiraly, J.; Porra, Veikko BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 167-170: ill

Modeling and simulation of circuits with shared structurally synthesized BDDs

Ubar, Raimund-Johannes; Jürimägi, Lembit; Raik, Jaan; Viies, Vladimir Microprocessors and microsystems 2017 / p. 56-61 : ill
<https://doi.org/10.1016/j.micpro.2016.09.006> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Modelling transients in oscillator circuits

Kukk, Vello NDES'97, Moscow, June 26-27 : posters 1997 / p. 520-525: ill

Multiple control fault testing in digital systems with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill
<http://dx.doi.org/10.1109/AQTR.2016.7501287>

Multiple fault analyses in logic circuits

Ubar, Raimund-Johannes IFAC-Symposium Discrete Systems : Dresden, 14.-19. 3. 77 1977 / p. [?]

Organ bio-impedance modelling with 3D mesh of equivalent circuits

Gordon, Rauno Proceedings of the XII International Conference on Electrical Bioimpedance & the V Conference on Electrical Impedance Tomography : ICEB/IEIT 2004 : June 20-24, 2004, Gdansk, Poland. Vol. 2 2004 / p. 715-718

Overcoming convergence problems in simulation

Aaltonen, Sakari BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 273-276: ill

Partition search for FSM low power synthesis

Sudnitsõn, Aleksander Proceedings of the 4th International Conference "Computer-Aided Design of Discrete Devices" : CAD DD'2001 : Minsk, Belarus, 2001. Vol. 1 2001 / p. 44-49

Performance optimization by Extended Peripheral Retiming

Fehlauer, Erhard; Rülke, Steffen; Franke, Günter BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 425-430: ill https://www.ester.ee/record=b2150914*est

Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia

2012 http://www.ester.ee/record=b2777270*est

Product and manufacturing in electronics : supplementary material in the subject "Technologies of electronic circuits"

Rang, Toomas 2003 https://www.ester.ee/record=b1766953*est

Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG

Palermo, N.; **Tihomirov, Valentin**; Copetti, Thiago; **Jenihhin, Maksim**; **Raik, Jaan**; **Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill
<http://dx.doi.org/10.1109/LATW.2015.7102405>

Research and training environment for digital design and test

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Proceedings of the Eighth IASTED International Conference on Computers and Advanced Technology in Education : August 29-31, 2005, Oranjestad, Aruba 2005 / p. 232-237 : ill
<https://ieeexplore.ieee.org/document/1408779>

Reuse-dominated synthesis of electronic designs

Conradi, Peter BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 431-435: ill https://www.ester.ee/record=b2150914*est

Scalable algorithm for structural fault collapsing in digital circuits

Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Orasson, Elmet**; **Raik, Jaan** 2015 IFIP/IEEE International Conference on Very Large Scale Integration (VLSI-SoC) : October 5-7, 2015, Daejeon, Korea 2015 / p. 171-176 : ill

A scalable technique to identify true critical paths in sequential circuits

Ubar, Raimund-Johannes; **Kostin, Sergei**; **Jenihhin, Maksim**; **Raik, Jaan** Proceedings 2017 IEEE 20th International Symposium on Design and Diagnostics of Electronic Circuit & Systems(DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 152-157 : ill
<https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=7934553>

7-valued algebra for transition delay fault analysis

Kõusaar, Jaak; **Ubar, Raimund-Johannes** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 89-92 : ill

Shared Structurally Synthesized BDDs for speeding-up parallel pattern simulation in digital circuits

Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Raik, Jaan** 2015 Nordic Circuits and Systems Conference (NORCAS) : NORCHIP & International Symposium on System-on-Chip (SoC) : 1st IEEE NORCAS Conference : 26-28 October 2015, Oslo, Norway 2015 / [4] p. : ill <http://dx.doi.org/10.1109/NORCHIP.2015.7364406>

SPICE-inspired fast gate-level computation of NBTI-induced delays in nanoscale logic

Kostin, Sergei; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 223-228 : ill

State of charge estimation for Li-ion batteries based on equivalent circuit diagrams and the application of a Kalman filter

Rahmoun, Ahmad; Biechl, Helmuth; **Rosin, Argo** 12th International Symposium "Topical Problems in the Field of Electrical and Power Engineering." Doctoral School of Energy and Geotechnology II : Kuressaare, Estonia, June 11-16, 2012 2012 / p. 125-128 : ill

Switched capacitor general immitance converter

Kängsep, Eiko; **Kukk, Vello** BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 483-486: ill https://www.ester.ee/record=b2150914*est

Symbolic test generation for hierarchically modeled digital systems

Zaugarov, Viktor 1993 https://www.ester.ee/record=b2090336*est

Synthesis of hierarchically testable FSM networks

Kasirova, Lilia; **Keevalik, Andres**; **Kruus, Margus** BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 347-352: ill

TCAD with device-circuit simulators for advanced process development, correlations between model parameters and optimization

Bubennikov, Alexander N. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 2 1994 / p. 517-522: ill https://www.ester.ee/record=b2150914*est

10th IEEE European Test Symposium

Ubar, Raimund-Johannes; Prinetto, Paolo; **Raik, Jaan** IEEE journal of design & test of computers 2005 / p. 480-481 : phot
<http://dx.doi.org/10.1109/MDT.2005.106>

Testing tools

Jutman, Artur Handbook of testing electronic systems 2005 / p. 361-365 : ill

Testing tools

Raik, Jaan Handbook of testing electronic systems 2005 / p. 373-378 : ill

A tool set for teaching design-for-testability of digital circuits

Kostin, Sergei; Orasson, Elmet; Ubar, Raimund-Johannes EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill <https://doi.org/10.1109/EWME.2016.7496466>

Transition delay fault simulation with parallel critical path back-tracing and 7-valued algebra

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan Microprocessors and microsystems 2015 / p. 1130-1138 : ill <https://doi.org/10.1016/j.micpro.2015.05.003> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Õkonoomsete negatiivse diferentsiaaltakistusega astmete ja elementide disainimine ja optimeerimine

Taniloo, Rainer 2005 https://www.ester.ee/record=b2073482*est

Генерирование тестов для цифровых схем при помощи модели альтернативных графов

Ubar, Raimund-Johannes Труды по электротехнике и автоматике : сборник статей. 14 1976 / с. 75-81 https://www.ester.ee/record=b2190768*est <https://digikogu.taltech.ee/et/Item/aa35e320-87b1-405b-9cac-3b90c51867d1>

Диалоговая система моделирования электронных схем "ПОИСК"

Laksberg, Edgar; Nelus, K.; Ess, Viktor Методы и устройства регистрации, передачи, обработки и представления информации 1986 / с. 63-68

Единый подход к синтезу тестов цифровых схем и систем

Ubar, Raimund-Johannes Межреспубликанская школа-семинар по технической диагностике, 8-12 октября 1984 года : тезисы докладов 1984 / с. 75-81 : илл https://www.ester.ee/record=b1237891*est

Импульсные устройства : лабораторная работа No 5 : триггеры на логических элементах

1988 https://www.ester.ee/record=b1224918*est

Исследование алгоритмов преобразования и аппроксимации параметров линейных систем и цепей на ЭВМ : автореферат ... кандидата технических наук (05.13.01)

Rüstern, Ennu 1976 https://www.ester.ee/record=b1301697*est

Исследование алгоритмов преобразования и аппроксимации параметров линейных систем и цепей на ЭВМ : диссертация на соискание ученой степени кандидата технических наук

Rüstern, Ennu 1975 https://www.ester.ee/record=b4630872*est

О выборе варьируемых элементов при оптимизации электронных схем

Laksberg, Edgar; Ess, Viktor Труды по радиотехнике. 3 1976 / с. 3-8 : илл https://www.ester.ee/record=b2190765*est <https://digikogu.taltech.ee/et/Item/051089c8-3240-47a7-84ae-2e65ba92e5fb>

Об общей постановке задач тестовой диагностики цифровых схем

Ubar, Raimund-Johannes Труды по электротехнике и автоматике : сборник статей. 14 1976 / с. 69-73 https://www.ester.ee/record=b2190768*est <https://digikogu.taltech.ee/et/Item/aa35e320-87b1-405b-9cac-3b90c51867d1>

Организация тестовых экспериментов цифровых систем на основе модели альтернативных графов

Lohuaru, Tõnu Межреспубликанская школа-семинар по технической диагностике, 8-12 октября 1984 года : тезисы докладов 1984 / с. 47-52 https://www.ester.ee/record=b1237891*est

Применение алгебры Буля при проектировании схем автоматики : конспект лекций

Agur, Ustus 1974 https://www.ester.ee/record=b1292481*est

Руководство по применению пакета прикладных программ анализа и оптимизации электронных схем "ПОИСК"

1983 https://www.ester.ee/record=b1271968*est

Символьное моделирование линейных электронных схем

Сусану, Георгий; Кицул, Игорь 35 научная конференция студентов втузов Эстонии, Латвии, Литвы, Белоруссии и Молдовы : [Таллинн, 1991] : доклады. Секция математики [и др.] 1991 / с. 26-30: ил

Структура и алгоритмы пакета прикладных программ анализа и оптимизации электронных схем "Поиск"

Laksberg, Edgar; Ess, Viktor Методы и средства обработки сигналов при наличии шумов 1982 / с. 31-38 https://www.ester.ee/record=b1312255*est <https://www.etera.ee/zoom/121735/view?page=1&p=separate&search=true&tool=search>

Тестовая диагностика цифровых устройств : учебное пособие. II, Синтез и анализ тестов. Дешифрация

диагностических экспериментов

Ubar, Raimund-Johannes 1981 https://www.ester.ee/record=b1326795*est